NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 765 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 735nm @ 0° AOI
        T(abs): =50% FOR 750±7.5nm @ 0° AOI

    S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
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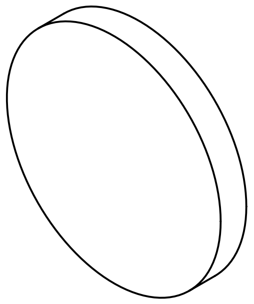

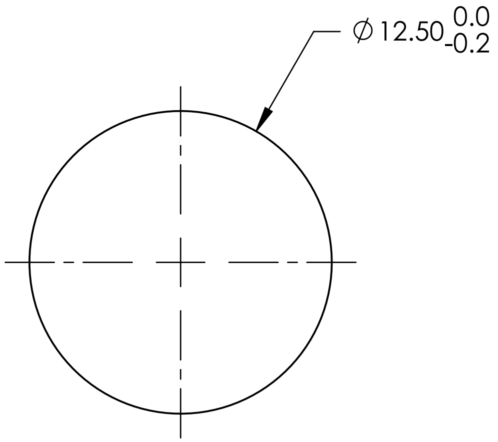

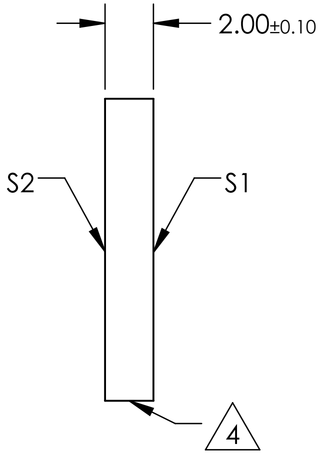

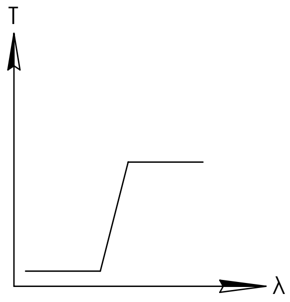

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 750nm, HIGH PERFORMANCE LONGPASS FILTER		
ALL DIMS IN	mm	DWG NO	66226	SHEET 1 OF 1	

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 815 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 785nm @ 0° AOI
        T(abs): =50% FOR 800±8nm @ 0° AOI

    S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
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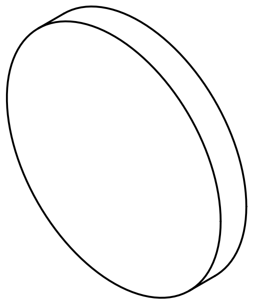

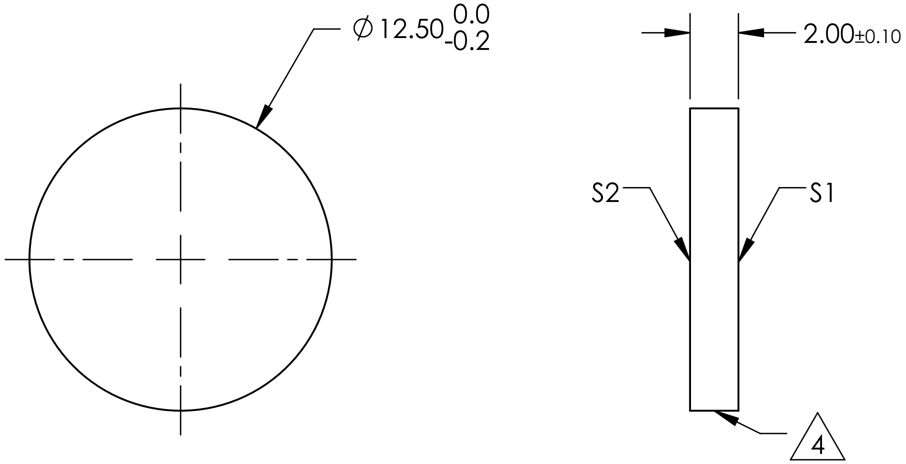

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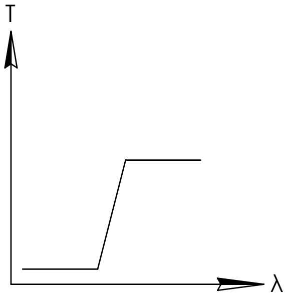
DIMENSIONS ARE FOR REFERENCE ONLY



LONGPASS FILTER

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 800nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	66227

SHEET
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
      T(avg): ≥91% FROM 865 - 1650nm @ 0° AOI
      T(avg): ≤0.01% FROM 200 - 835nm @ 0° AOI
      T(abs): =50% FOR 850±8.5nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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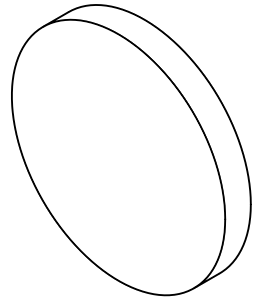

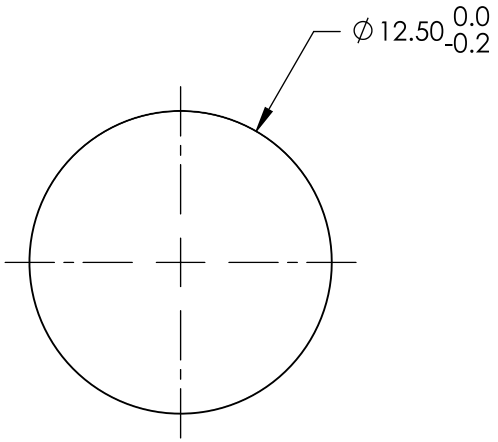

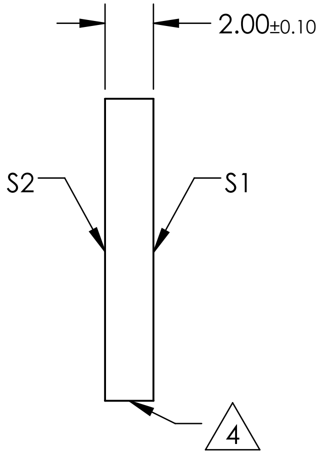

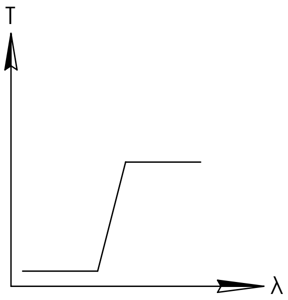

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 850nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	66228

SHEET
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 915 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 880nm @ 0° AOI
        T(abs): =50% FOR 900±9nm @ 0° AOI

    S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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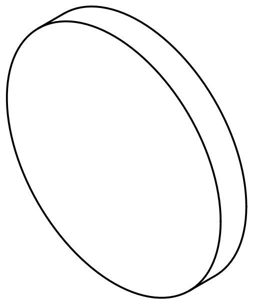

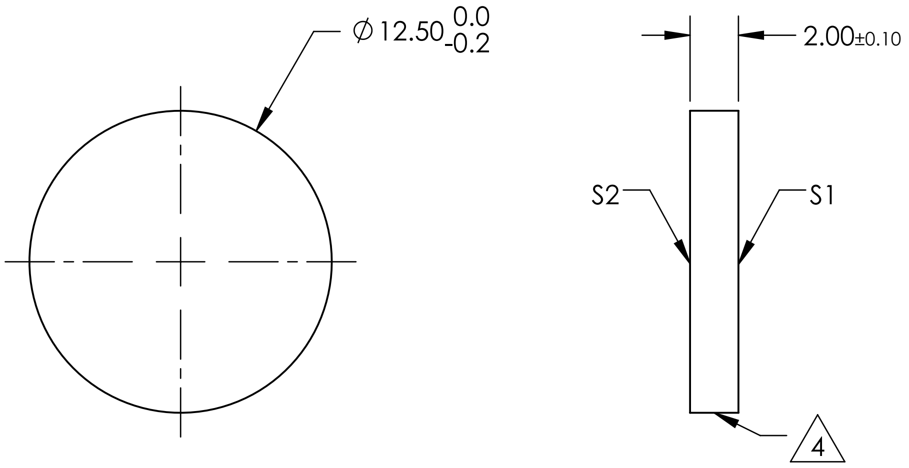

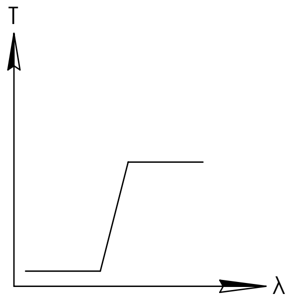

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 900nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN: mm

DWG NO: 66229

SHEET 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
     T(avg): ≥91% FROM 965 - 1650nm @ 0° AOI
     T(avg): ≤0.01% FROM 200 - 930nm @ 0° AOI
     T(abs): =50% FOR 950±9.5nm @ 0° AOI

   S2:SINGLE LAYER MgF2

△4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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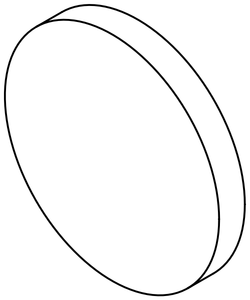

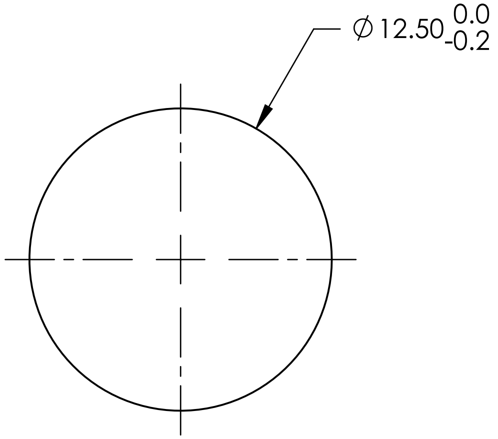

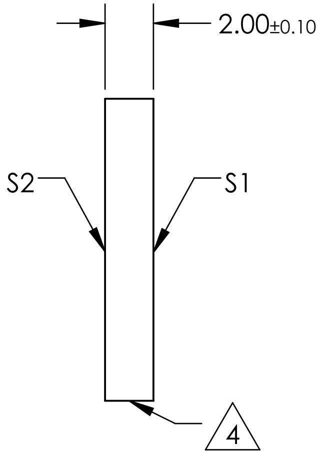

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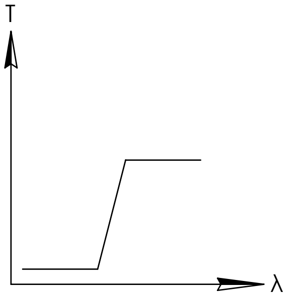

LONGPASS FILTER

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 950nm, HIGH PERFORMANCE LONGPASS FILTER	
ALL DIMS IN	mm	DWG NO	66230	SHEET 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 1020 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 980nm @ 0° AOI
   T(abs): =50% FOR 1000±10nm @ 0° AOI

   S2:SINGLE LAYER MgF2

△4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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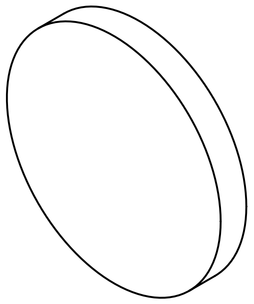

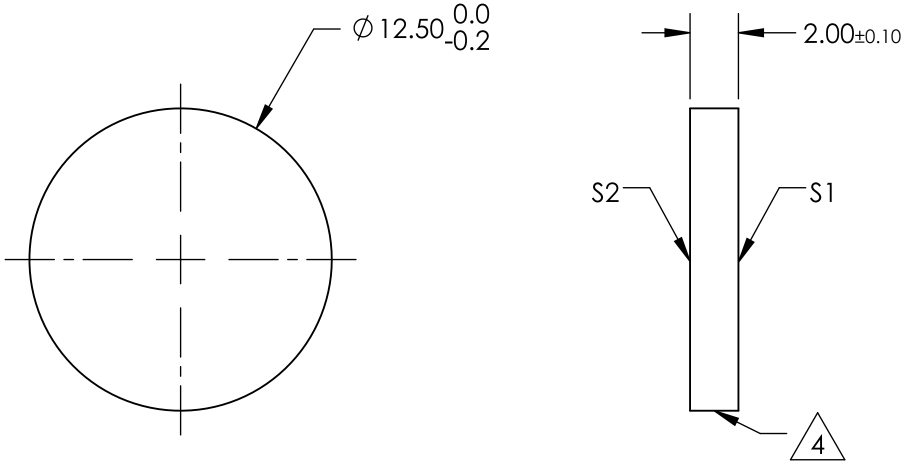

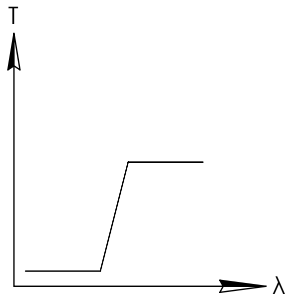

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 1000nm, HIGH PERFORMANCE LONGPASS FILTER	
ALL DIMS IN	mm	DWG NO	66231	SHEET 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 1070 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 1030nm @ 0° AOI
   T(abs): =50% FOR 1050±10.5nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. △ FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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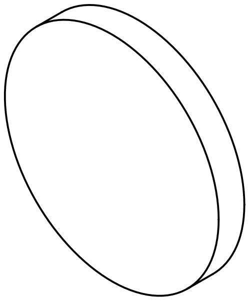

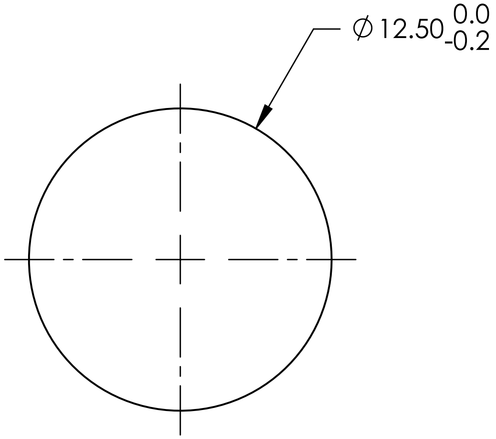

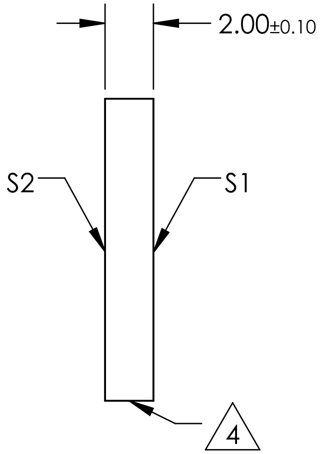

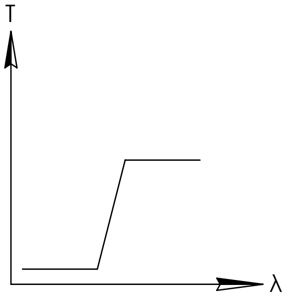

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 1050nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	66232

SHEET
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 1120 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 1080nm @ 0° AOI
   T(abs): =50% FOR 1100±11nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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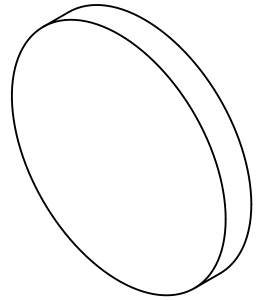

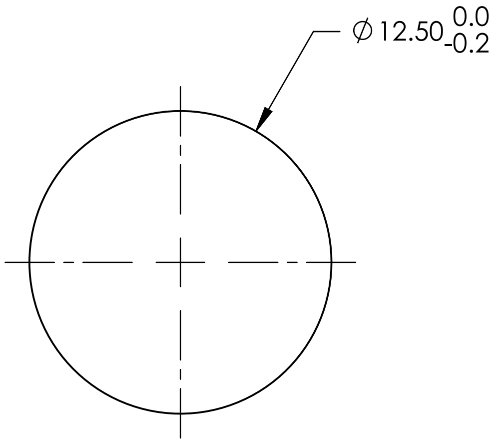

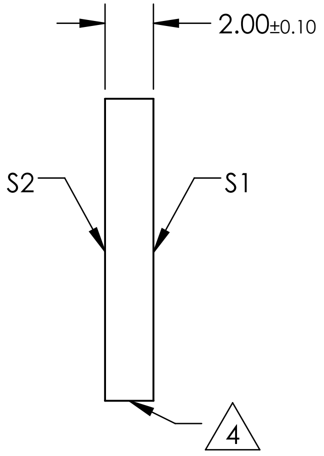

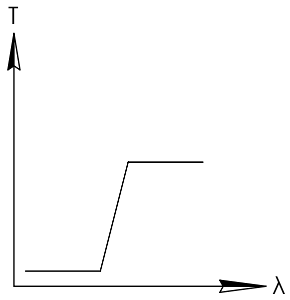

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 1100nm, HIGH PERFORMANCE LONGPASS FILTER		
ALL DIMS IN	mm	DWG NO	66233	SHEET 1 OF 1	

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 735 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 705nm @ 0° AOI
   T(abs): =50% FOR 725±7.25nm @ 0° AOI

   S2:SINGLE LAYER MgF2

△4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
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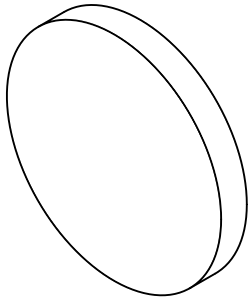

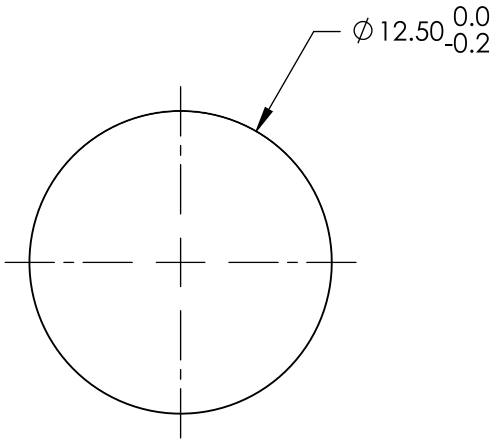

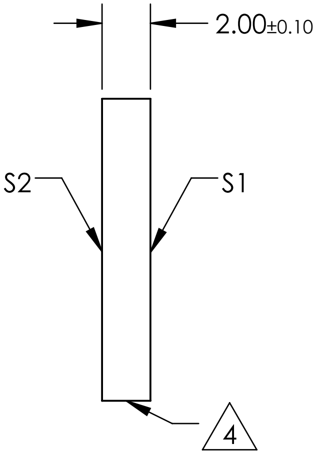

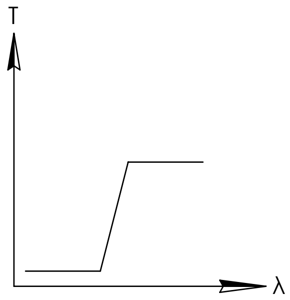

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 725nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	86060

SHEET
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 790 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 760nm @ 0° AOI
   T(abs): =50% FOR 775±7.75nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
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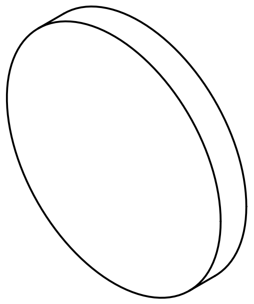
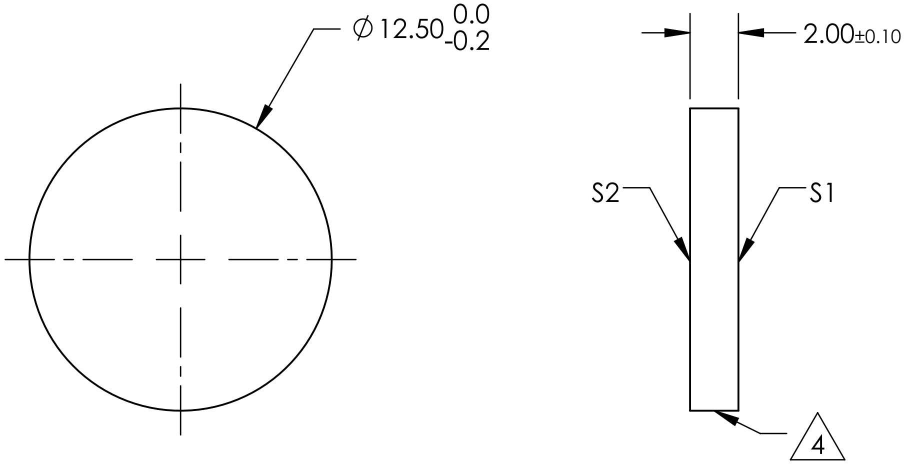
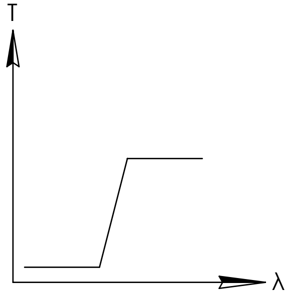
PARTS TO THIS DRAWING







LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 775nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN: mm

DWG NO: 86061

SHEET 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 840 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 805nm @ 0° AOI
        T(abs): =50% FOR 825±8.25nm @ 0° AOI

    S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

FOR INFORMATION ONLY:
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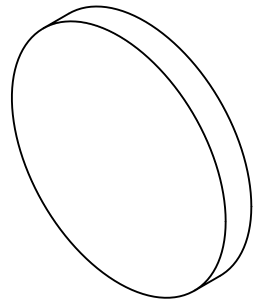

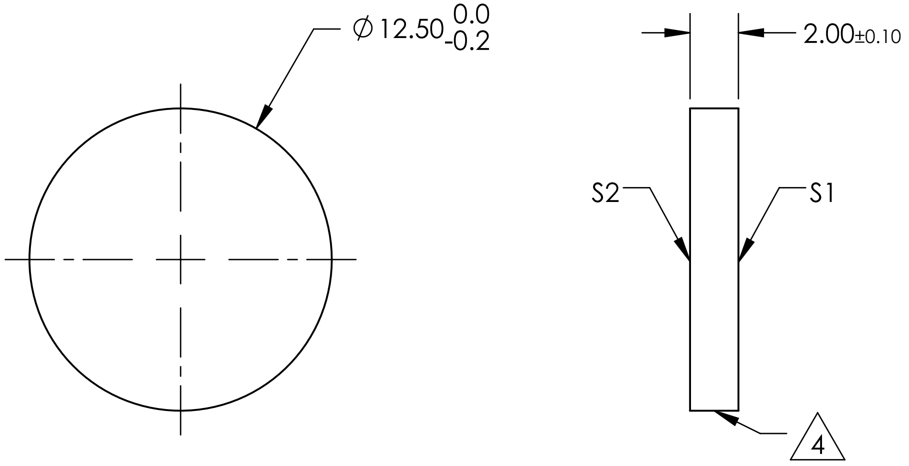

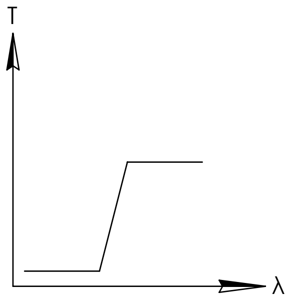

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 825nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	86062

SHEET
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 890 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 860nm @ 0° AOI
   T(abs): =50% FOR 875±8.75nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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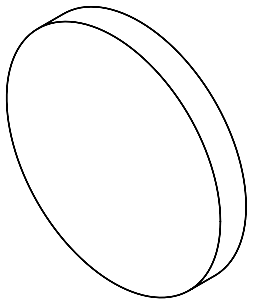

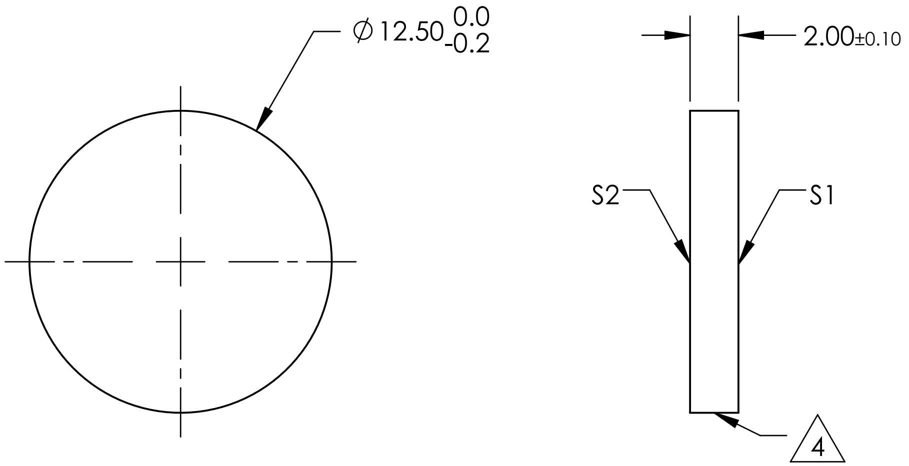

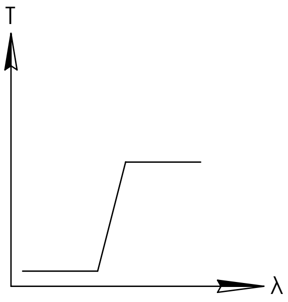

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

LONGPASS FILTER

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 875nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN: mm

DWG NO: 86063

SHEET 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 940 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 905nm @ 0° AOI
        T(abs): =50% FOR 925±9.25nm @ 0° AOI

    S2:SINGLE LAYER MgF2

△4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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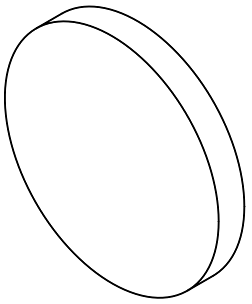

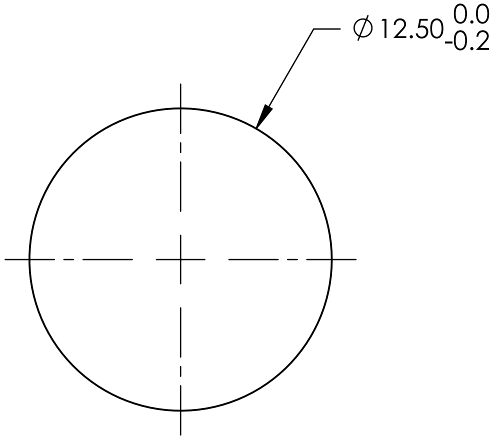

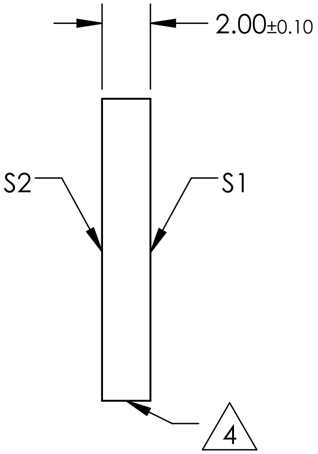

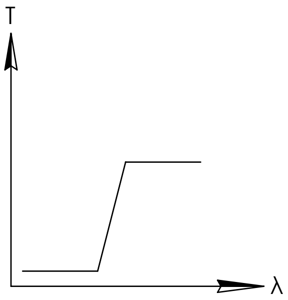

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

LONGPASS FILTER

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION		TITLE	Ø12.5mm, 925nm, HIGH PERFORMANCE LONGPASS FILTER
ALL DIMS IN	mm	DWG NO	86064

SHEET
1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 990 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 955nm @ 0° AOI
        T(abs): =50% FOR 975±9.75nm @ 0° AOI

    S2:SINGLE LAYER MgF2
4. △ FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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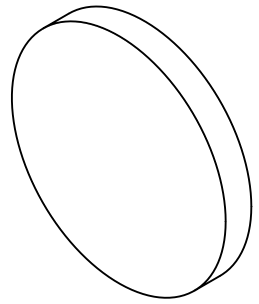

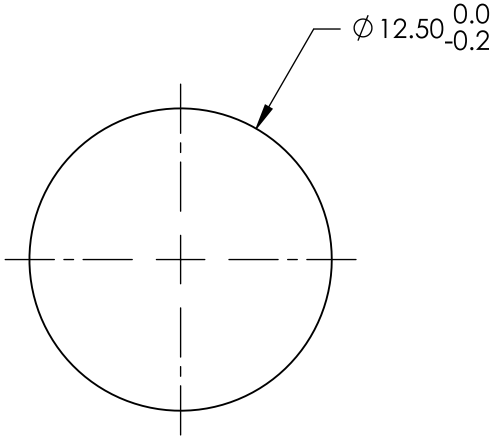

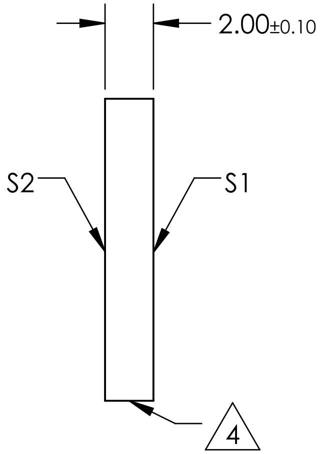

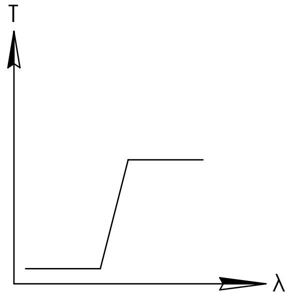

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 975nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN: mm

DWG NO: 86065

SHEET 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
   S1: HARD DIELECTRIC SPUTTERED
   T(avg): ≥91% FROM 1045 - 1650nm @ 0° AOI
   T(avg): ≤0.01% FROM 200 - 1005nm @ 0° AOI
   T(abs): =50% FOR 1025±10.25nm @ 0° AOI

   S2:SINGLE LAYER MgF2
4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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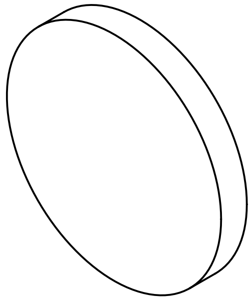

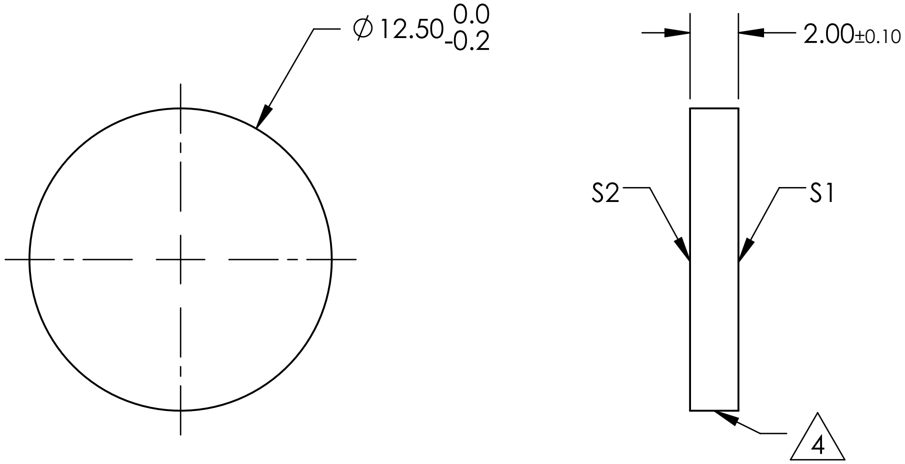

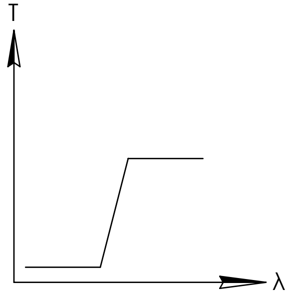

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 1025nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN: mm

DWG NO: 86066

SHEET 1 OF 1

NOTES:

1. SUBSTRATE
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)
    S1: HARD DIELECTRIC SPUTTERED
        T(avg): ≥91% FROM 1095 - 1650nm @ 0° AOI
        T(avg): ≤0.01% FROM 200 - 1055nm @ 0° AOI
        T(abs): =50% FOR 1075±10.75nm @ 0° AOI

    S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE
5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
7. ROHS COMPLIANT

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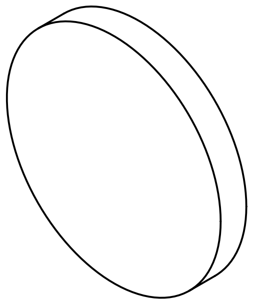

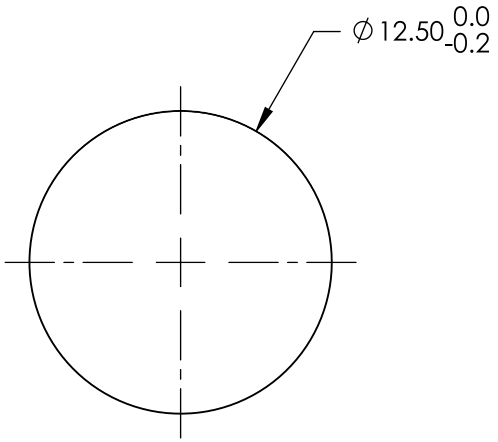

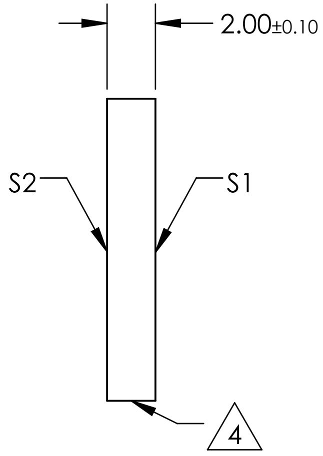

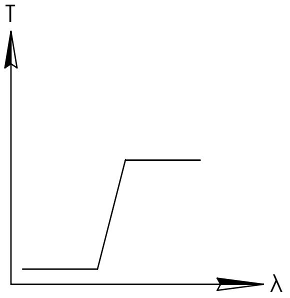

LONGPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV A	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION

TITLE: Ø12.5mm, 1075nm, HIGH PERFORMANCE LONGPASS FILTER

ALL DIMS IN mm

DWG NO 86067

SHEET 1 OF 1